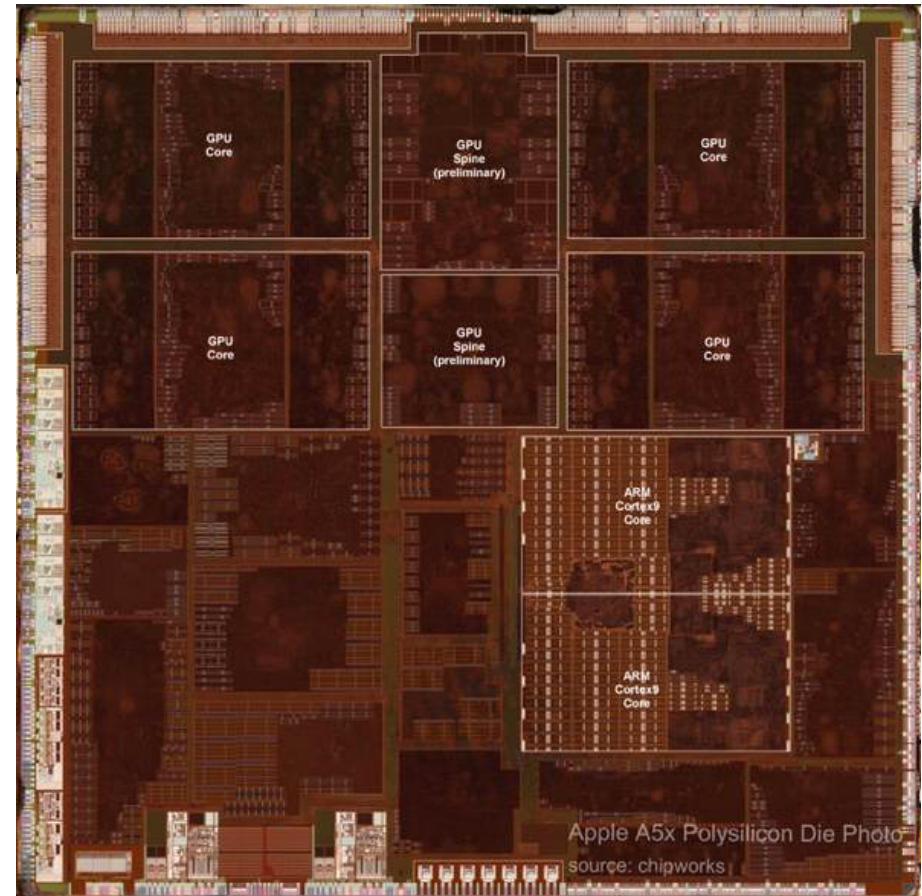


**EE-382M**  
**VLSI-II**  
**Early Design Planning for:**  
**Physical Design (PD)**

**Spring 2017**

**Mark McDermott**  
**Jacob Abraham**  
**Gian Gerosa**



**Apple A5X Die Photo**

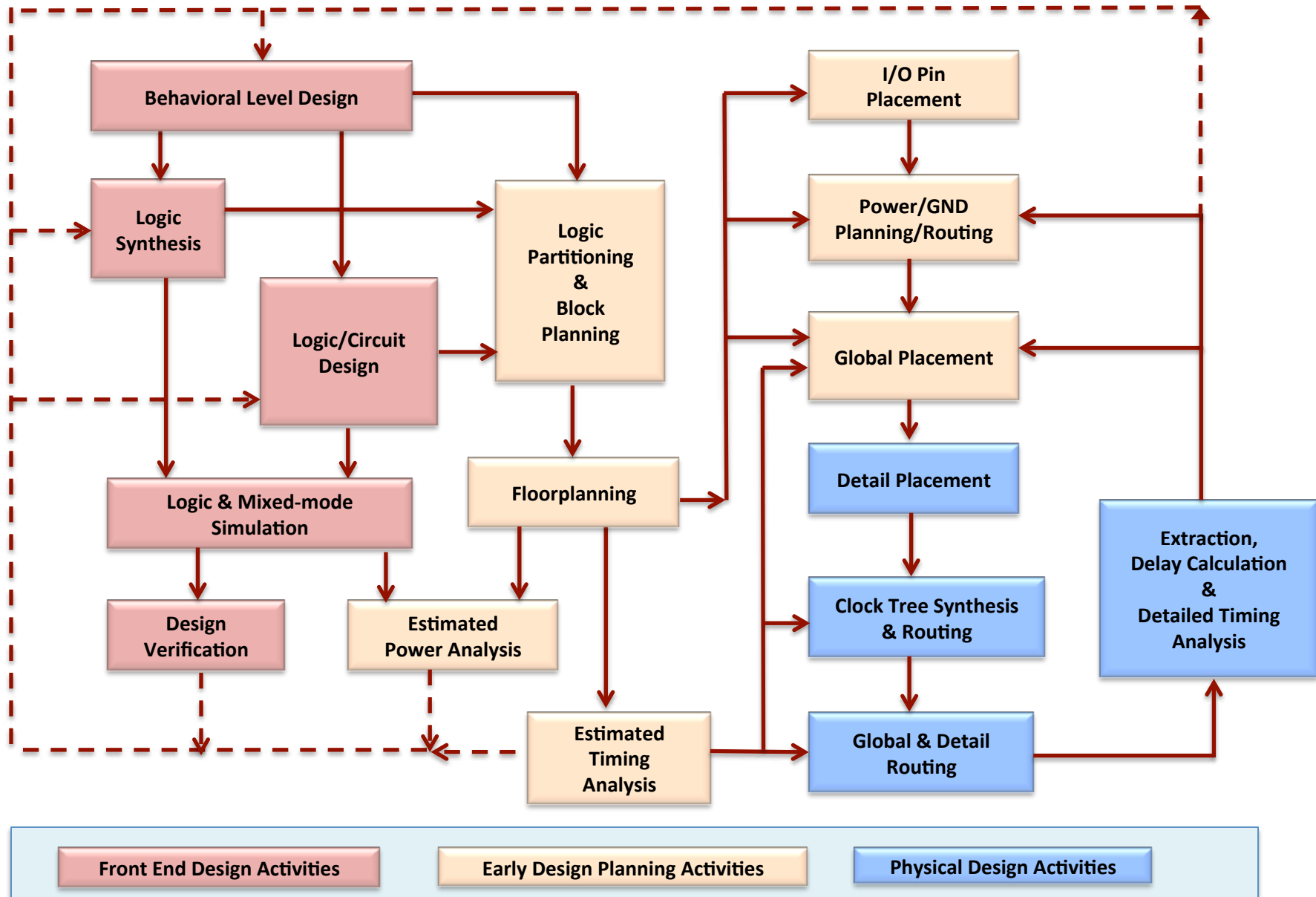
# Agenda

---

- **Design flow review**
- **Physical design**
- **Floorplanning**
- **Metal planning**
  - Clocks
  - Power grid
- **Memory array planning**

- **EDP – Early Design Planning**
- **PD – Physical Design**
- **FE – Front End**
- **BE – Back End**
- **SOC – System-on-Chip**
- **SC – Standard Cell**
- **SDP – Structured Datapath**
- **STA – Static Timing Analysis**
- **.LIB – STA Library**
- **ABGEN – Abstract Generator**
- **APR – Auto Place & Route**
- **LEF – Library Exchange Format**
- **DEF – Design Exchange Format**
- **TTM – Time to Money**

# Design Flow Review



# Agenda

---

- Design flow review
- **Physical design**
- Floorplanning
- Metal planning
  - Clocks
  - Power grid
- Memory array planning

# PD is handled by the Integration Team

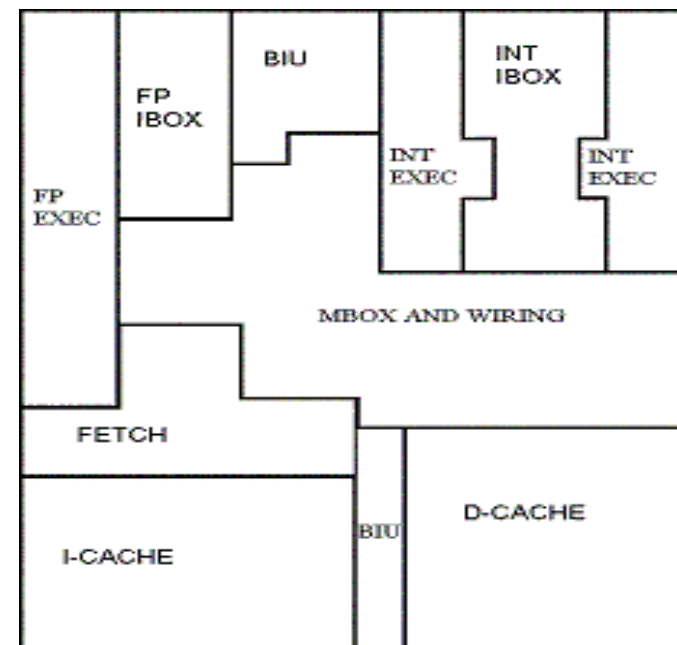
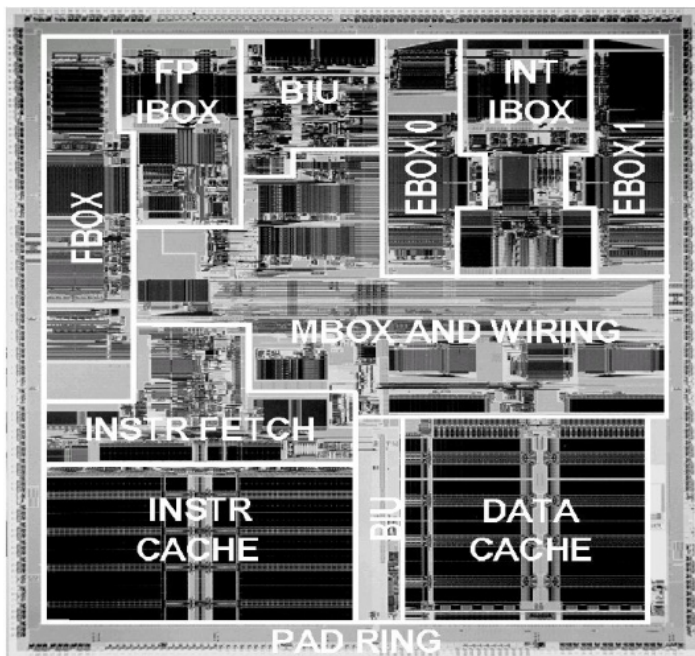
---

- **Integration teams are responsible for:**
  - Doing a floor plan of the top level of the chip
  - Characterizing the top-level routing delays and determining the assertions and constraints for each cluster.
    - **They will be working with each cluster to optimize the constraints**
  - Designing the clock routing structure
  - Determining the clock regeneration circuitry
  - Determining the reset logic
  - Designing the power grid
  - Determining global clock and signal route power estimation
  - Generating the power budget for each cluster
  - Generating the area budget for each cluster

**NOTE: There are typically between 40 – 60 floorplans generated during the course of a chip design.**

# PD-EDP Activities

- **PD-EDP activities include:**
  - Detailed floorplan of the block level components.
  - A reasonably detailed top-level floorplan using the cluster abstracts followed by final block synthesis and AP&R using a 32/28nm std-cell library
  - Memory blocks built with Synopsys memory compiler (SAED-MC)
  - Approximate clock routing at the top-level
  - Approximate Power-GND routing at the top level



- **The types of data that are required to start a physical design are:**
  - Technology and library files
  - Circuit description of the design in the form of netlist representation
  - Floorplan constraints
  - Timing and Design Rule Constraints
- **Technology and library files:**
  - Manufacturing grid
  - Routing layer definition & routing grid
  - Standard cell placement tile
  - Placement and routing blockage layer definition
  - Via definition
  - Conducting layer density rule
  - Metal layer slotting rule
  - Routing layer physical profile
  - Antenna definition
  - Required manufacturing cells such as fiducials, alignment markings, Intra-Die-Monitoring cells, Power rail monitoring cells, etc.
  - C4/wafer bump constraints and last-metal layout rules.

# PD Prerequisites (cont.)

---

- **Circuit description of the design in the form of netlist representation:**
  - Gate level HDL Model
    - Schematic based
    - Synthesis generated
- **Floorplan constraints (Chip & Block Level):**
  - Power grid
  - Clocking
  - Signal Routing including pre-routes & shielding requirements
  - Structured Data-path area
  - Random logic area
  - White space
  - “Thru-block” routing
  - Identify power grid and clock-domain ‘islands’
    - Synchronous and asynchronous regions
    - Determine signal level shifters and clock-domain-crossing checks
      - Synchronizers may be required, or special clock budgeting when crossing different clock frequencies.

# PD Prerequisites (cont.)

---

- **Two basic types of design constraints:**
  - Timing constraints
  - Design rule constraints
- **Timing constraints utilized by physical design tools include:**
  - System clock definition and clock delays
  - Cycle time and clock budgets (based on actual variability circuit simulations of sequential elements) for MIN and MAX DELAY
  - Multiple cycle paths
  - Input and output delays
  - Minimum and maximum path delays
  - Input transition and output load capacitance
  - False paths
- **Design rule constraints include:**
  - Maximum number of fan-outs
  - Maximum transitions
  - Maximum capacitance
  - Max wire length

# PD Implementation Options

- **Synthesis – Standard Cell (SC)**
  - Cell layout comes from a shared cell library
  - Automated cell selection and placement
  - Automated placement and routing (APR) between cells
  
- **Structured Datapath(SDP)**
  - Cell layout comes from a shared cell library
  - Manual cell selection and relative placement
  - Automated routing between cells
  
- **Custom Design (CD)**
  - Cell layout is unique for each application
  - Manual cell selection and placement
  - Manual routing between cells



Increasing  
Design Effort  
(and Density)

# PD Implementation Options (cont)

	CD	SDP	SC
RTL Coding	M	M	M
Logic Minimization	M	M	A
Cell Placement	M	M	A
Device Sizing	M	A	A
Layout	M	A	A

A = Automatic

M = Manual

	CD	SDP	SC
Timing	Best	Better	Worst
Density	Best	Better	Worst
Design Time	Worst	Better	Best
Revisions	Terrible	Tolerable	Best

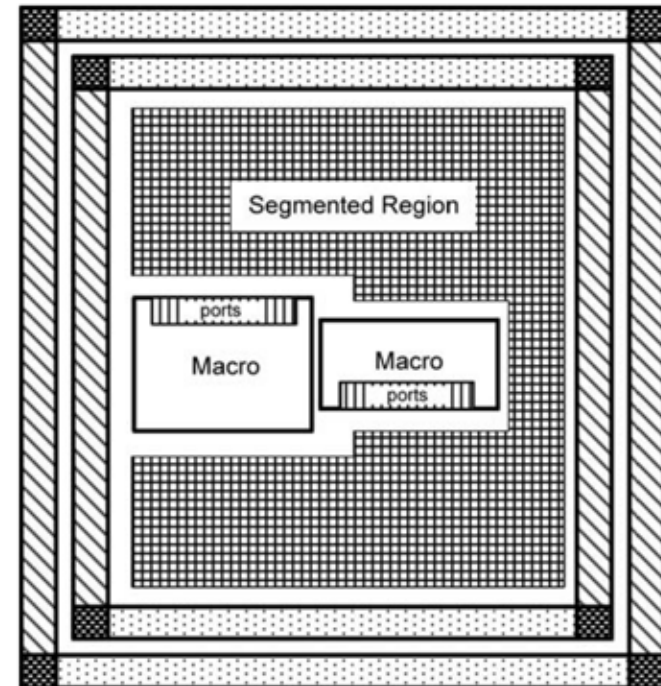
# Agenda

---

- Design flow review
- Physical design
- **Floorplanning**
- Metal planning
  - Clocks
  - Power grid
- Memory array planning

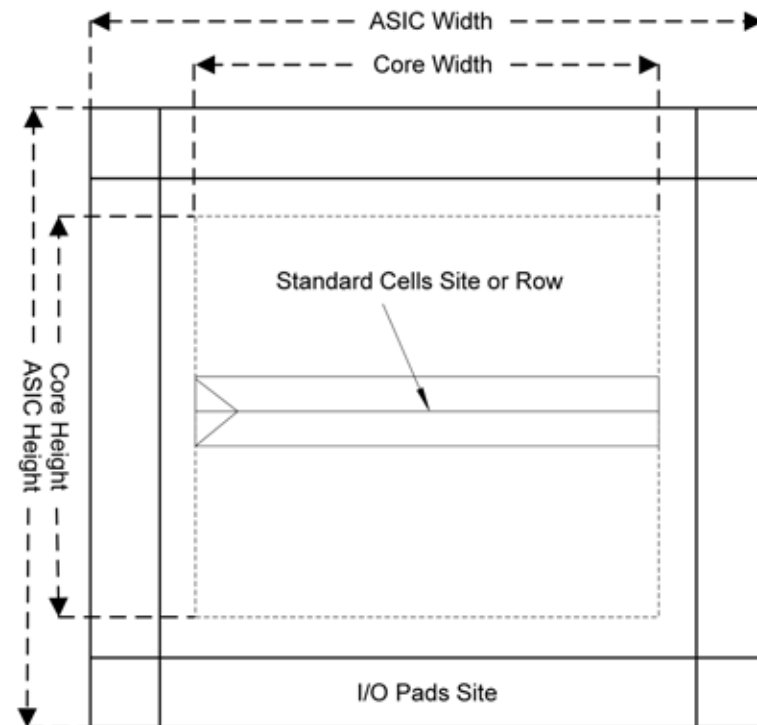
# Floorplanning 101

- **Determine block sizes**
  - Function of SC pitch, Cell Placement, RLM, SC/SDP, Custom/ Memory Block Sizing and Block Routing Overhead (Signals, Clocking, Power)



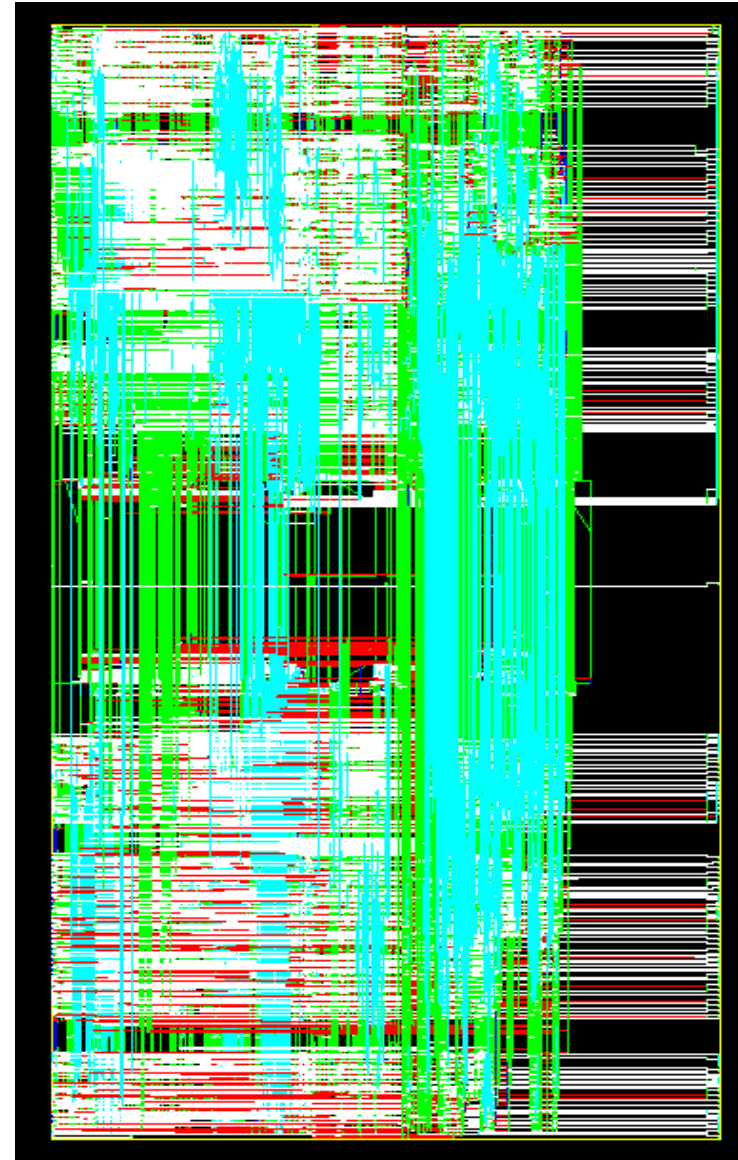
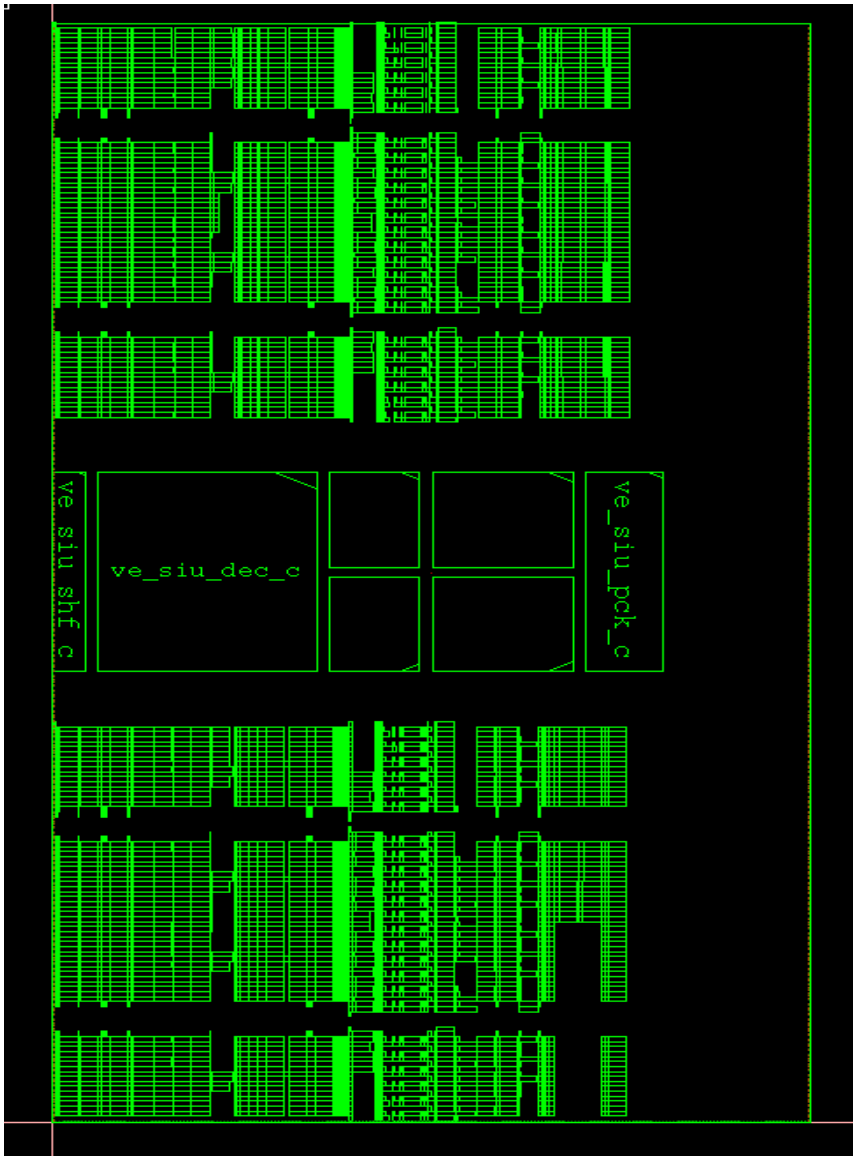
# Floorplanning 101

- **Determine block sizes**
  - Function of SC pitch, Cell Placement, RLM, SC/SDP, Custom/ Memory Block Sizing and Block Routing Overhead (Signals, Clocking, Power)
- **Determine core size**
  - Function of #Blocks, Block sizes, Block Aspect Ratios, Global Routing Overhead (Signals, Clocking, Power)
- **Determine I/O ring size**
  - Function of the number of I/O, Number of Power Pins and Placement

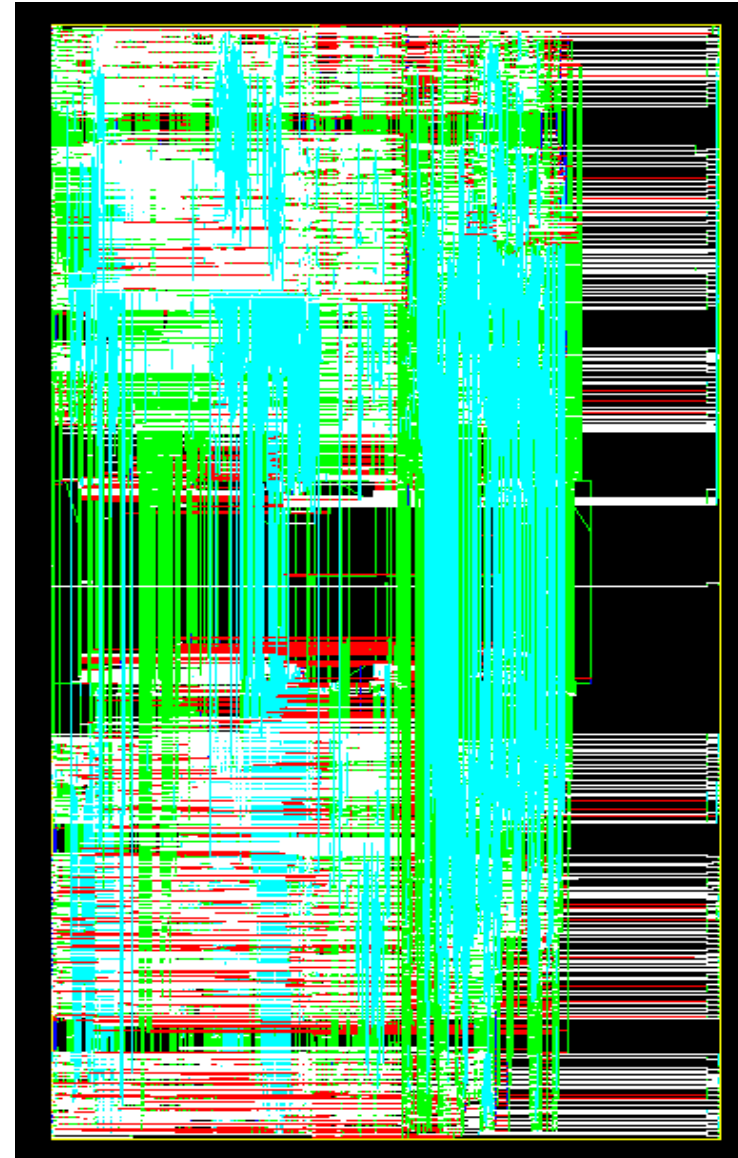
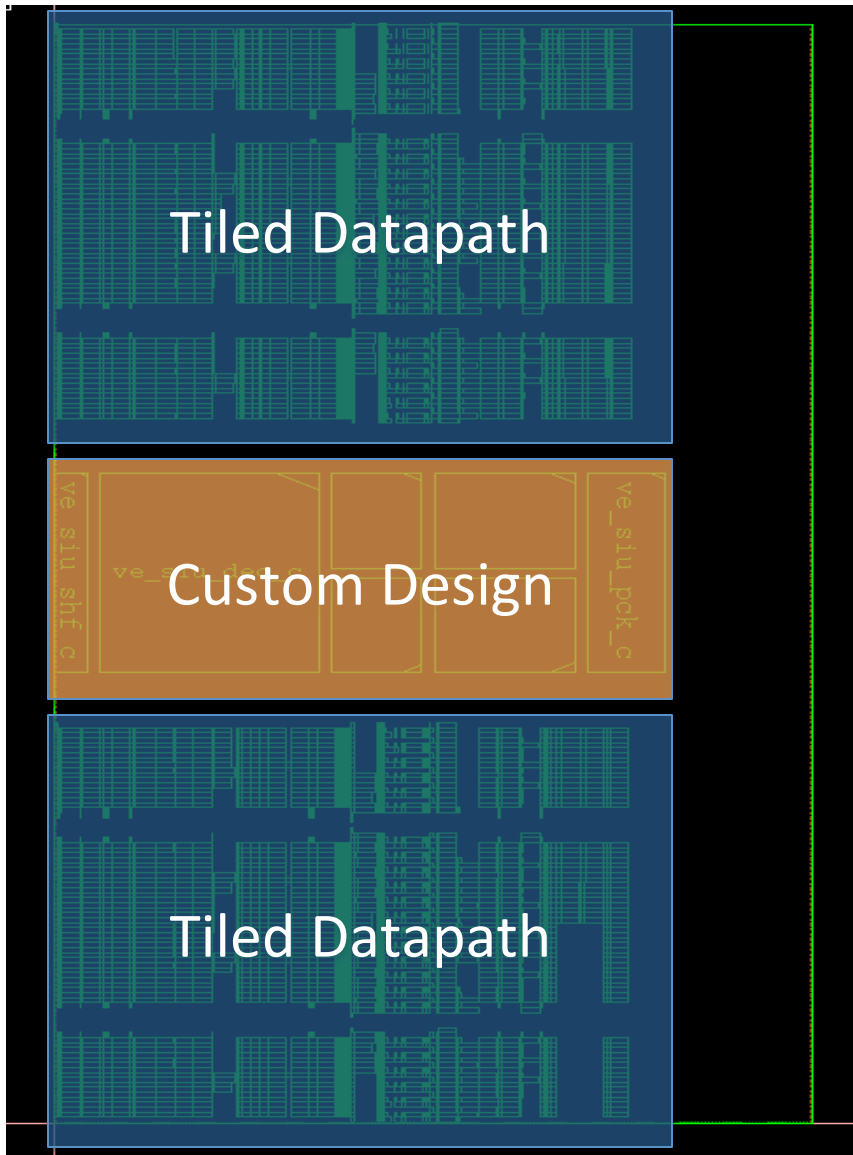


- **Start with the critical path!**
  - Use “regions” to place cells to limit the wire load on the critical path
    - Move less critical blocks out of the way
  - Pre-route critical paths
  
- **Pre-place critical macro cells to “guide” placement tool**
  - Can set the one of the dimensions of the chip
  
- **Pre-place clock generators to limit clock wire load**
  - Again, place most critical local clock buffers (LCB) first if area is tight
  - Ideally there should be minimal side loads

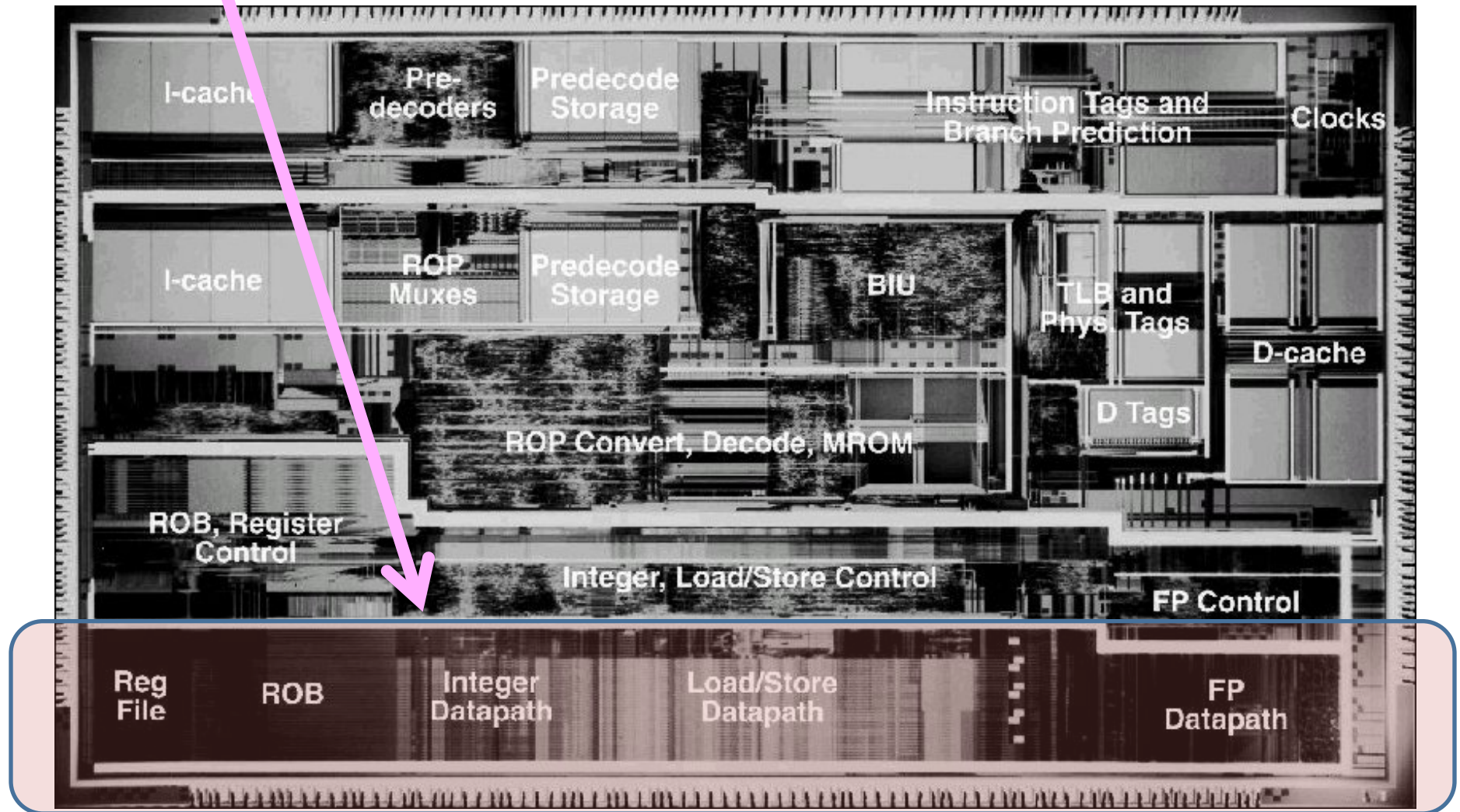
# Cell Placement & Routing (example)



# Cell Placement & Routing (example)



# Hard Macros Defining Width of Chip



**AMD K5 Datapath**

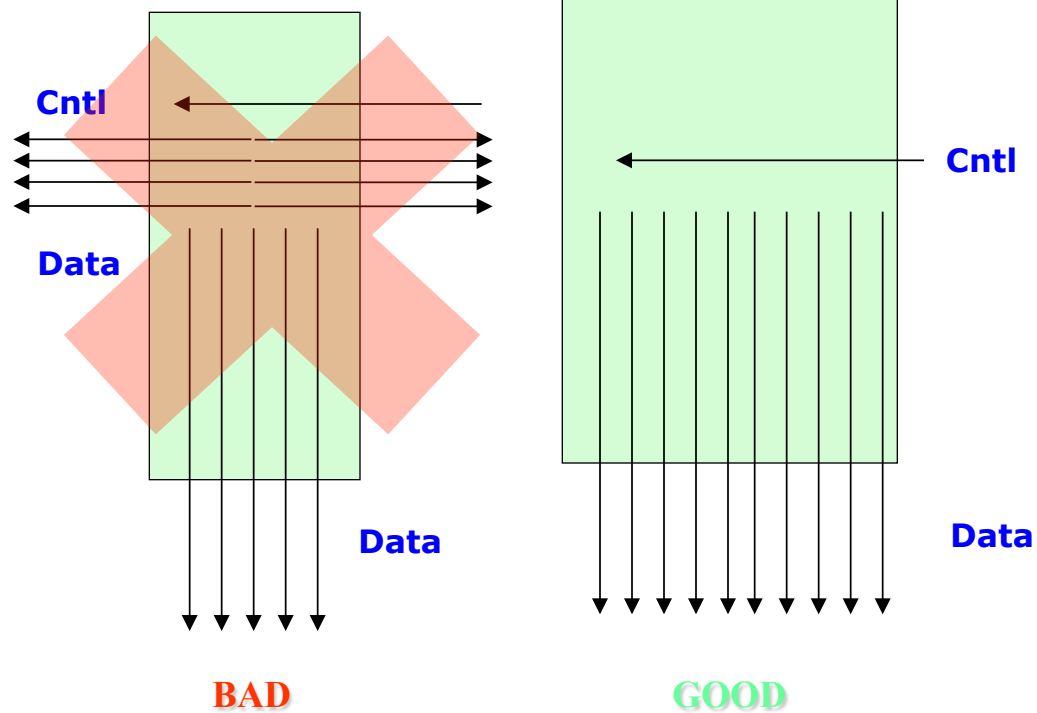
# Agenda

---

- Design flow review
- Physical design
- Floorplanning
- **Metal planning**
  - Clocks
  - Power grid
- Memory array planning

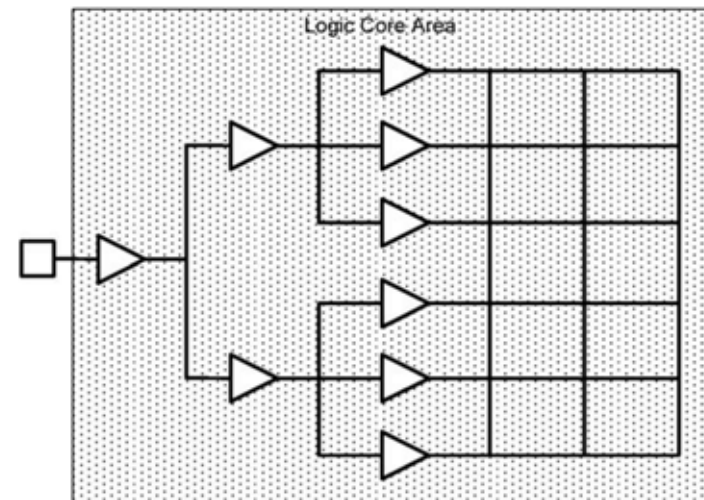
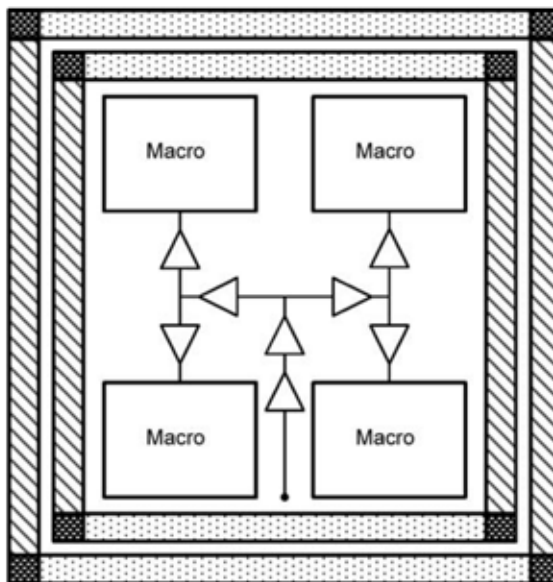
- **Metal layer, width, spacing and shielding are negotiable**
  - “Negotiable” means you have to plead your case to the integration leader
  - All of these impose a physical constraint for layout
- **Typical 8 layer metal layer allocation**
  - M1,M2 : Local routing (standard cell)
  - M3,M4, M5, M6 : Data and control
  - M7,M8 : Power, Ground, Clock, Reset, etc
  - Assume HVH routing:
    - Metal-1: Horizontal
    - Metal-2: Vertical
    - Metal-3: Horizontal
    - Metal-4: Vertical
    - .....
- **Use standard 'HALO' cells to make the resulting 'floor-plannable' objects 'snap' to the desired power and routing grids.**
  - Added to the boundary of all custom layouts (as well as synthesized blocks).

## Avoid bi-directional dataflow



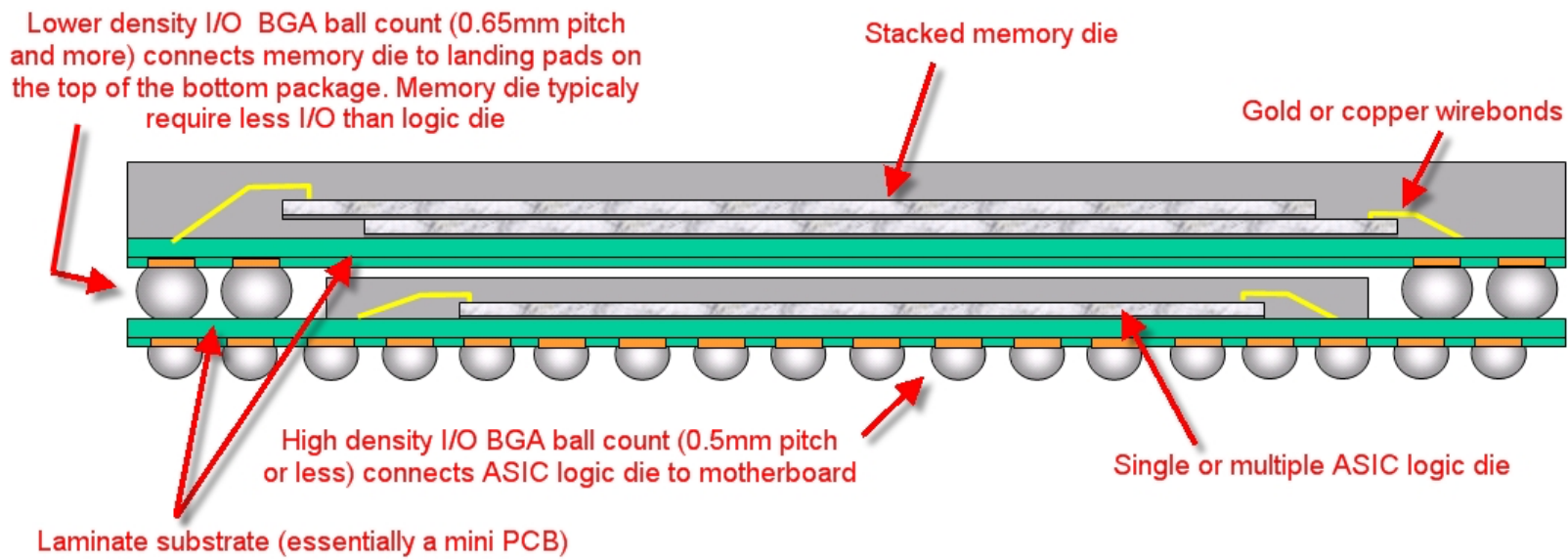
# Chip & Block Level Clock Routing

- Watch out for the clock, it's your most critical net
- Make sure the physical design treats it accordingly
- Help reduce clock power by eliminating unnecessary load
- Make sure the clock net has enough via coverage
- Use a combination of Global (Chip) and Block Level Clock distribution



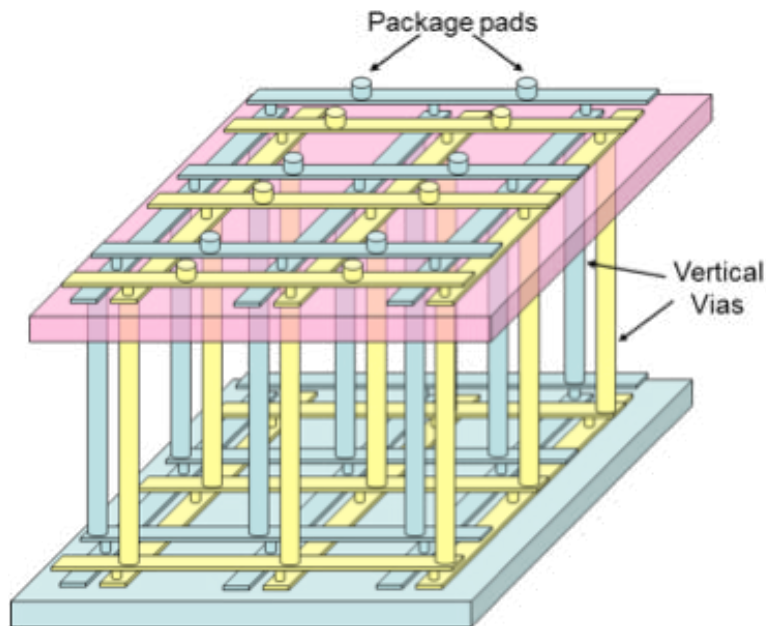
# Power Grid

- Delivers current from the package and C4 bumps to the transistors
- Designed to deliver “typical” current density to the devices
- Increasing current density by arraying large devices can cause you to exceed the power grid’s nominal design



# Power Grid Considerations

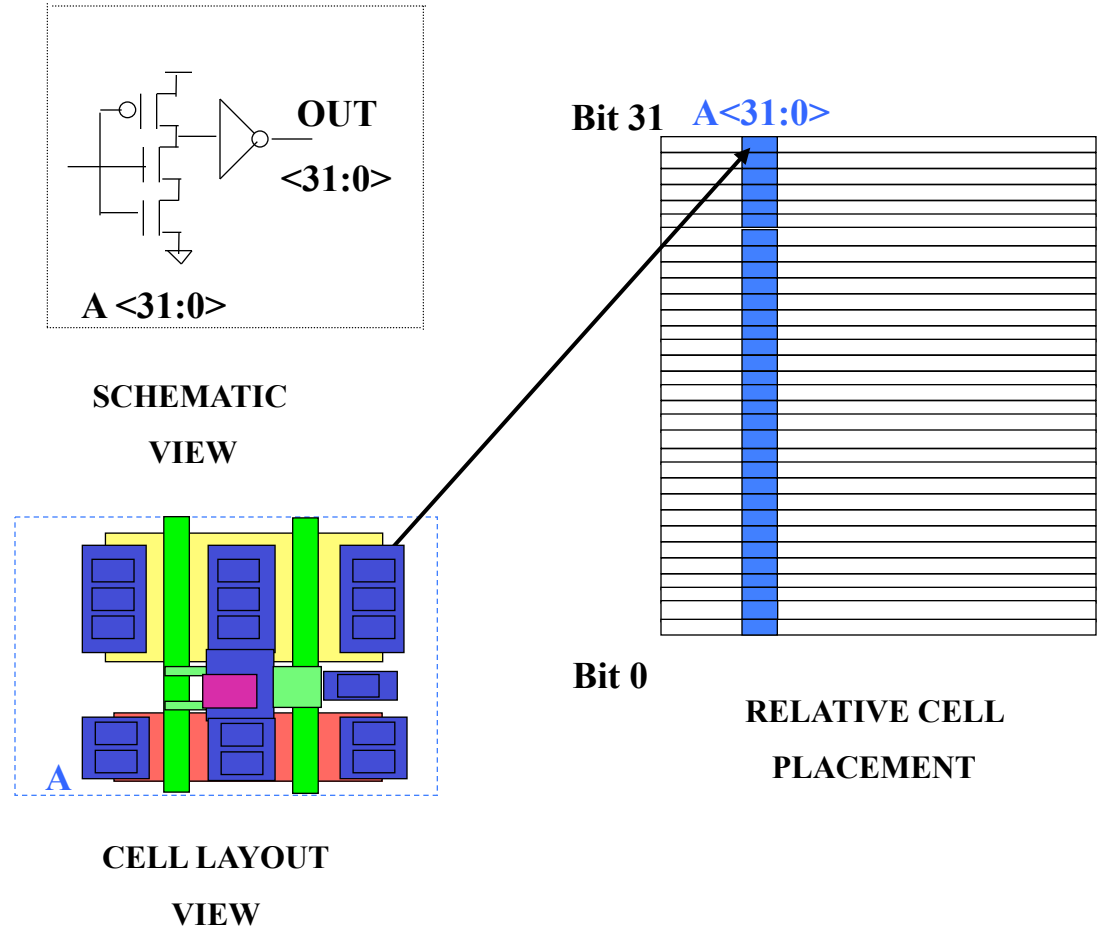
- Be very careful arraying large drivers
- Follow the % power guidelines for the power grid
- Try to keep temporal relationships between arrayed drivers
- Consider the physical impact on the grid by your design
- Be prepared to make the grid more robust to compensate for marginal grids



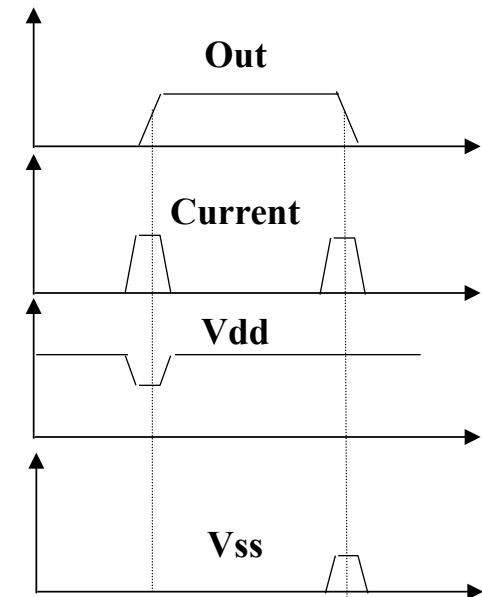
Think of the grid as a straw between the C4 and the devices.

Too many devices drawing current through the same via or too narrow a via can cause devices to starve and the supply to dip or crater!

# Power Grid Considerations (cont)

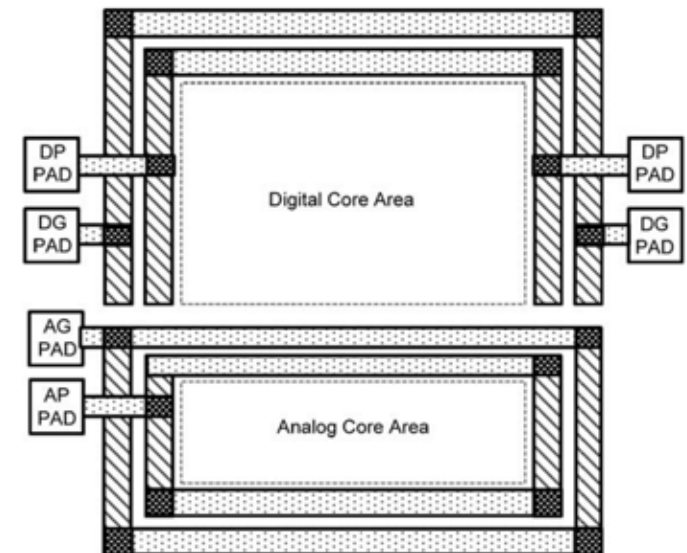
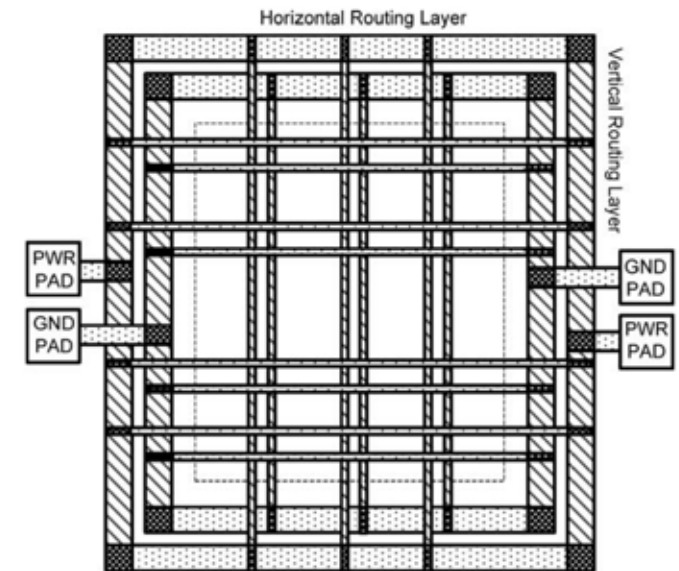


When large, arrayed drivers pull on the same rail, supply bounce can occur degrading performance and causing supply offset noise



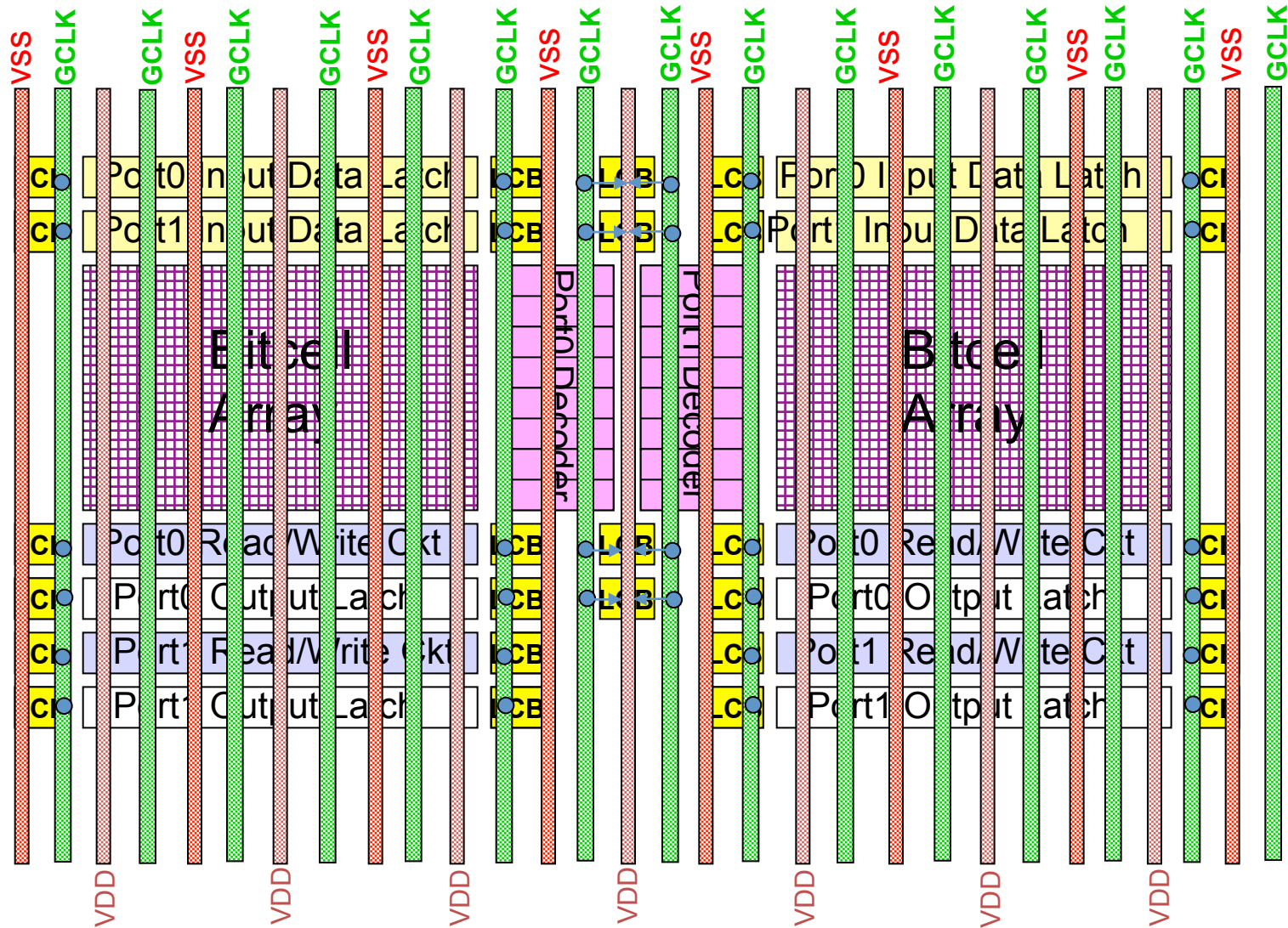
# Chip level power routing

- **Power busses are a combination of rings and/or grids.**
  - Rings are generally in the I/O ring.
  - Grids are used at the chip and block level
  - Grid pitch is set by horizontal and vertical routing resource requirements
  
- **Special consideration needs to be taken for multiple power domains.**
  - There can be any number of power domains depending on the system architecture
  - Analog blocks require isolation rings
  - Interfaces between blocks require level shifters



# Power/Clock Grid Example

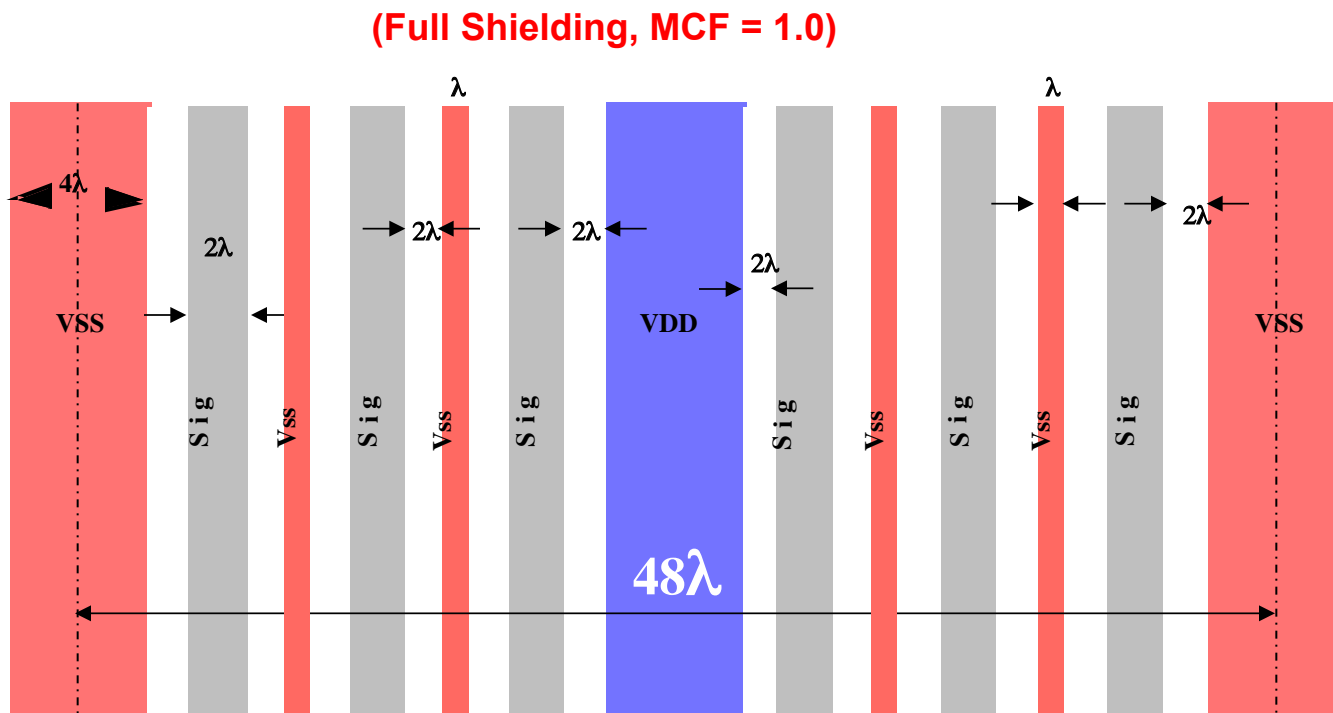
- Clock grid is interleaved between VDD and VSS on metal6



- **Intentionally routing signals to control the effective line-to-line capacitance seen during switching.**
  
- **Requires designers to constrain the physical assembly done by routing tools or physical design specialists (PDSs).**
  
- **Falls into one of three categories:**
  - Physical shielding - signals are routed next to a power rail
  - Logical shielding - signals are routed by logically related signals
  - Temporal shielding - signals are routed by temporally distinct signals

# Power/Ground/Signal Shielding Example

- Shielding takes up significant routing resources.
- Global M6 routes over the array should have minimal coupling noise to array bitlines.



\* Where  $\lambda$  is minimum critical dimension for width/space

# Agenda

---

- Design flow review
- Physical design
- Floorplanning
- Metal planning
  - Clocks
  - Power grid
- **Memory array planning**

# Array Area Estimation

---

## ■ Cell Area

- 6T bitcell dimensions strongly dependent on technology
  - Manufacturing/FAB provides this
- Multiported cells are wire limited and can be easily calculated
  - Cell Height is a function of  $\{MH\_Pitch * (Wordlines + Shields)\}$
  - Cell Width is a function of  $\{MV\_Pitch * (Bitlines + Datalines + Shields)\}$

## ■ Local Bitline Receivers and Dataline drivers

- Height of array is increased by local bitline receivers
  - $NumReadPorts * NumEntries / CellPerLBL$

# Array Area Estimation

---

- **Decoder & Wordline Repeaters**
  - **Width of array is increased by the decoder**
    - **Decoder width is a function of number of ports**
    - **20% of total array width is a reasonable estimate**
  - **Width of array is increased by wordline repeaters**
    - **Typically no more than 32 to 64 bitcells on a single wordline (limits rise/fall time of selected row)**

# Array Area Estimation

## ■ Cell Height & Width Calculation

- Cell Height = {MH\_Pitch\*(Wordlines + Shields)}
- MH\_Pitch\*[ (#R + #W) + WL\_shield\*(#R + #W + 1)]
- Cell Width = {MV\_Pitch\*(Bitlines + Datalines + Shields)}
- MV\_Pitch\*[ (#R + Rd\_shield\*#R + 1) + (#W + Wr\_shield\*#W + 1)]

### – Where

- #R            Number of Read Ports
- #W            Number of Write Ports
- WL\_shield   Read wordline shield factor
- Rd\_shield   Read bitline shield factor
- Wr\_shield   Write dataline shield factor
- MH\_Pitch   Wordline Pitch
- MV\_Pitch   Bitline Pitch

# SRAM Array Area Estimation

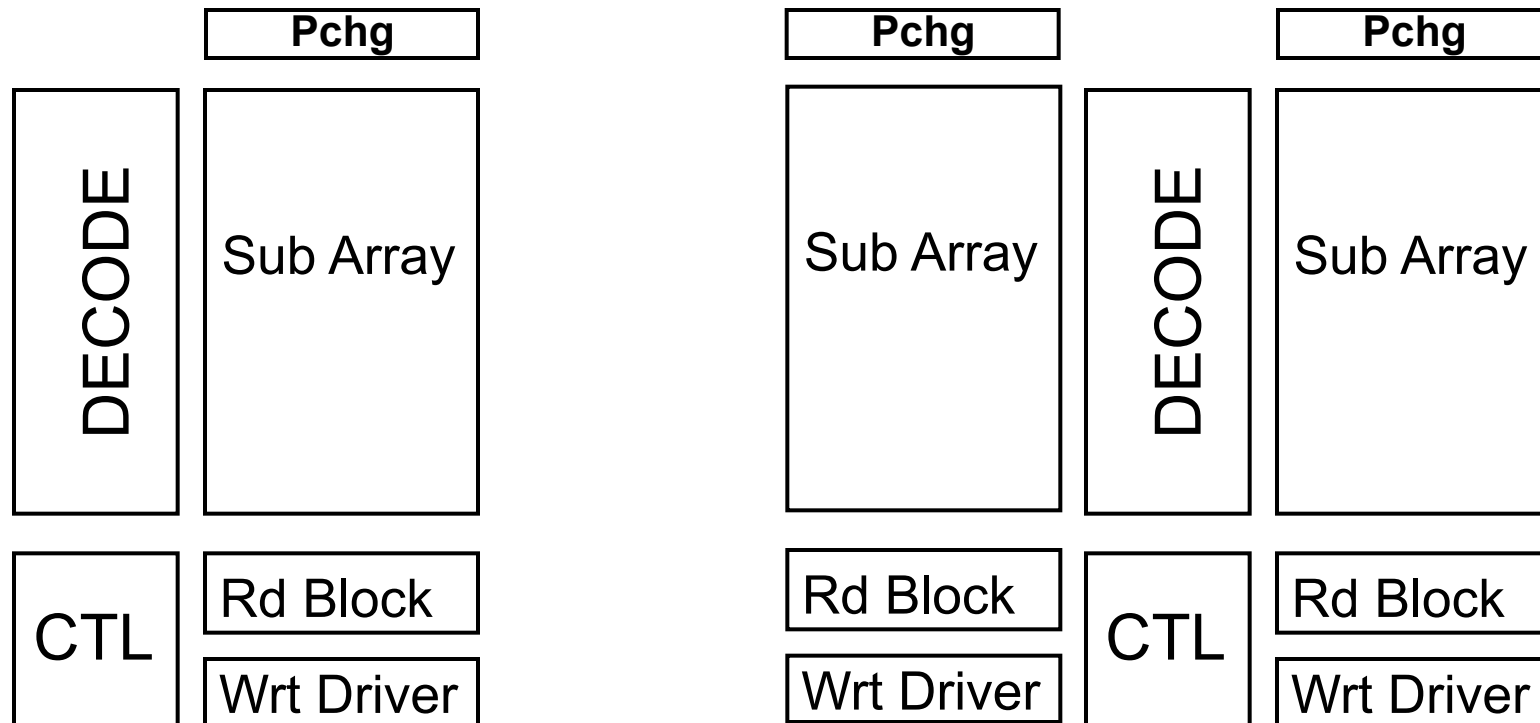
## ■ Estimate sub-array first:

- # 6T bitcells \* bitcell area + wordline & column decoders + sense-amp + read/write sequentials.
- The decoders + sense-amps + sequentials are typically 15% of the subarray bitcell area.
- Use an ‘array efficiency’ factor to calculate the total SRAM array area; this includes clock buffers, address decoders, control logic, repeaters, routing, etc.; typical numbers are in the range of ~60%.

## ■ EXAMPLE:

- A 16KB L1 cache with four 4KB subarrays; each subarray is comprised of 128 bitcells/column and 256 bitcells/wordline; the 6T bitcell area in this 45 nm CMOS technology is 0.38 mm<sup>2</sup>.
  - Bitcell subarray =  $0.38 \text{ mm}^2 * 128 * 256 = 12,452 \text{ mm}^2$
  - Subarray =  $1.15 * 12,452 = 14,320 \text{ mm}^2$
  - 4 subarrays =  $4 * 14,320 = \sim 57,280 \text{ mm}^2$
  - 16KB L1 cache =  $57,280 / 0.60 = 95,467 \text{ mm}^2$

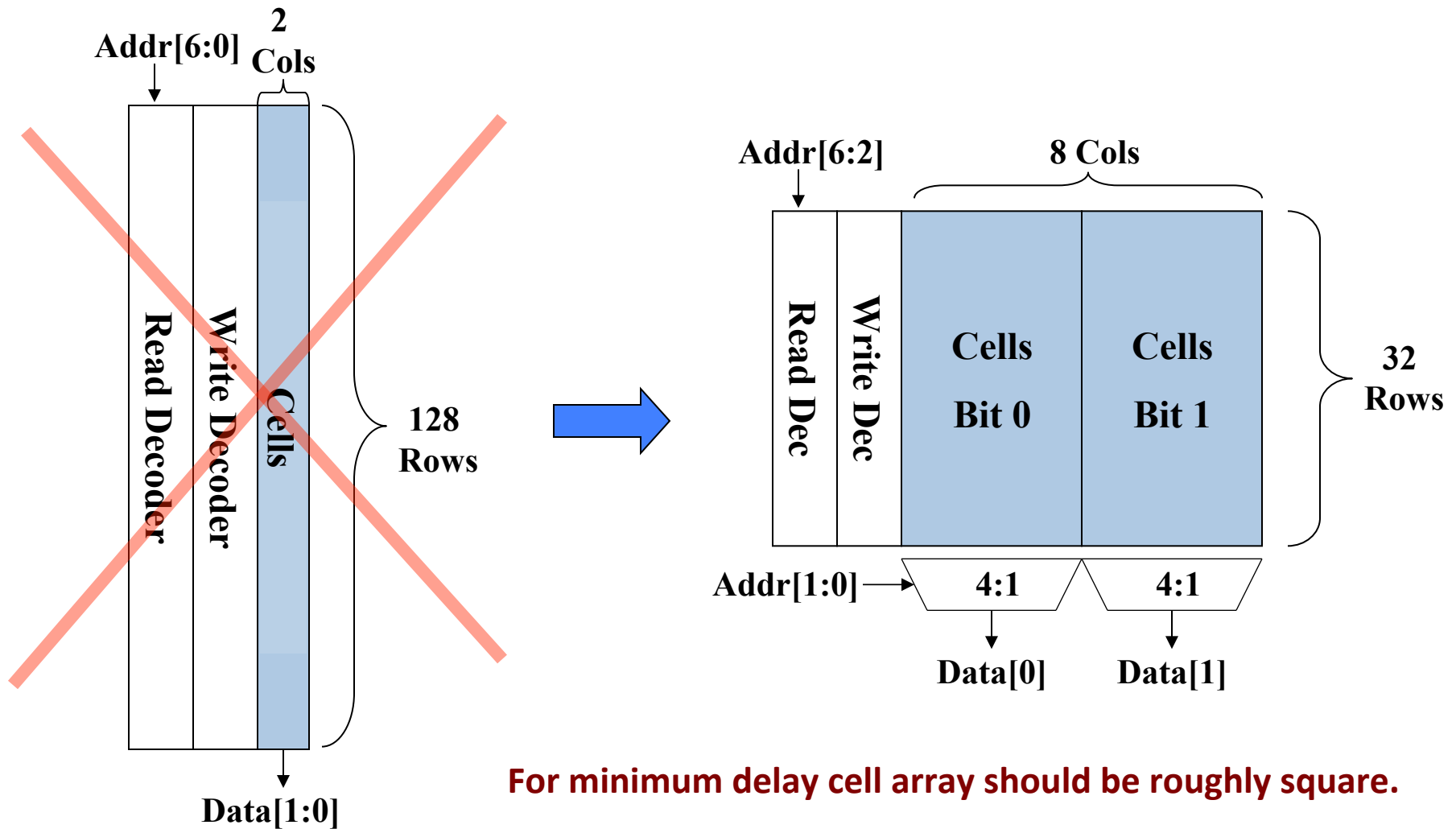
# Floorplan Options



## Possible Large-Signal Array Floorplans

Array Area Calculator provides dimensions for these blocks

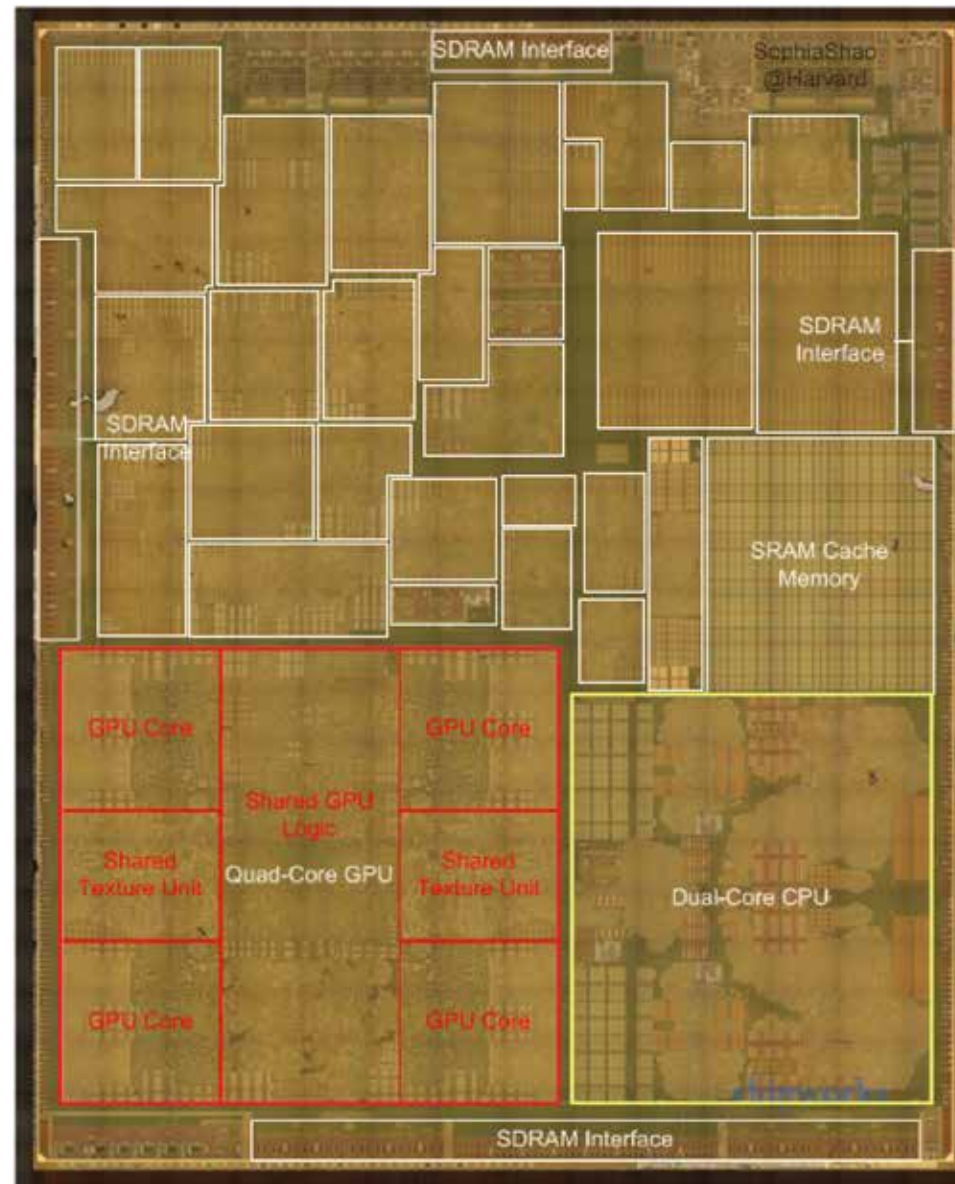
# Dual-Ended Cell Column Muxing



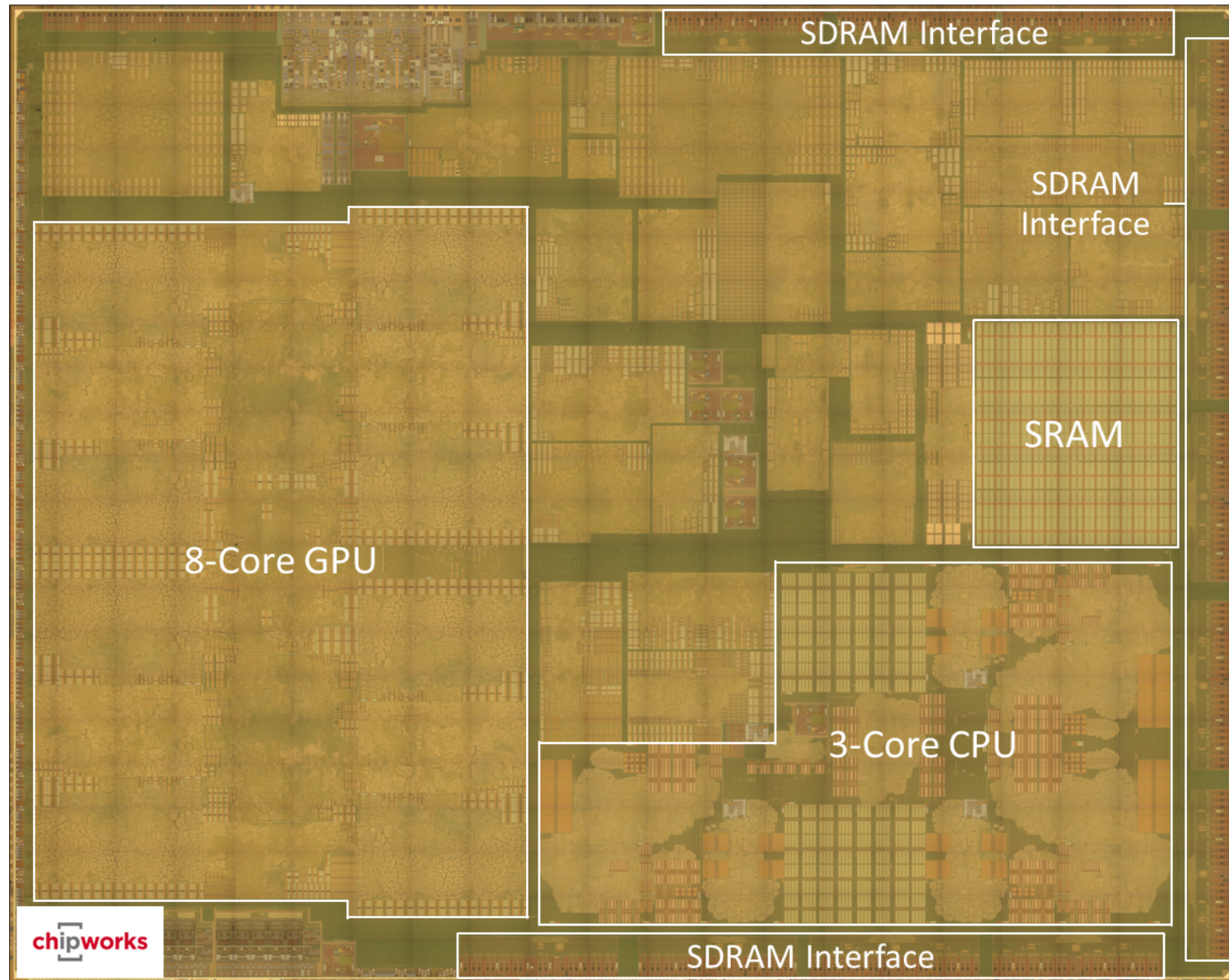
- **Early design planning and improved layout density can have a significant impact**
  - Die size, profit & power are impacted by layout density
  - Schedule is impacted by implementation decisions
  
- **Floorplanning can significantly impact chip performance**
  - Shielding can help timing and noise sensitive circuits
  - Carefully floorplanning critical paths can help reduce wire loads
  - Reducing clock routing can reduce clock skew and clock power

## Eye candy: Floorplan examples

# Apple A8 SOC (for iPhone)

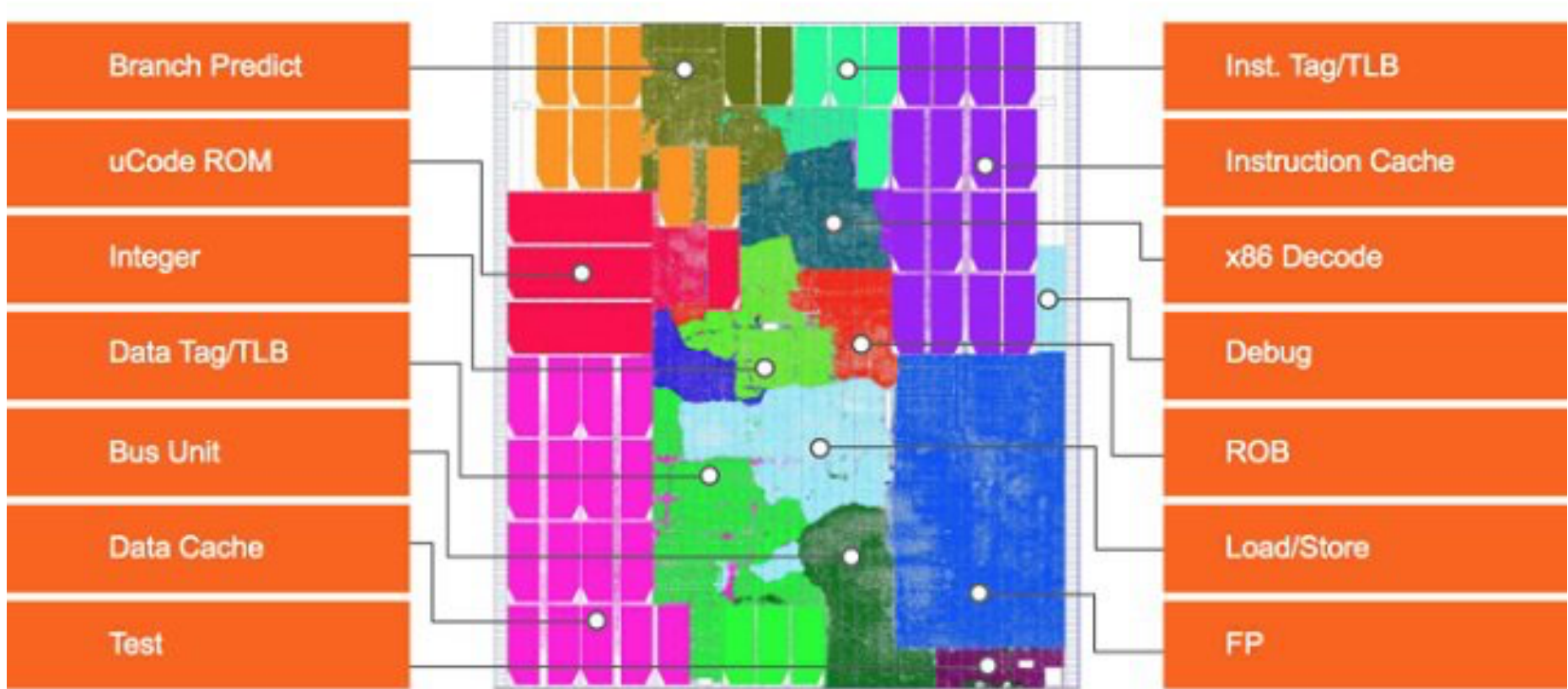


# Apple A8X SOC (for iPad)

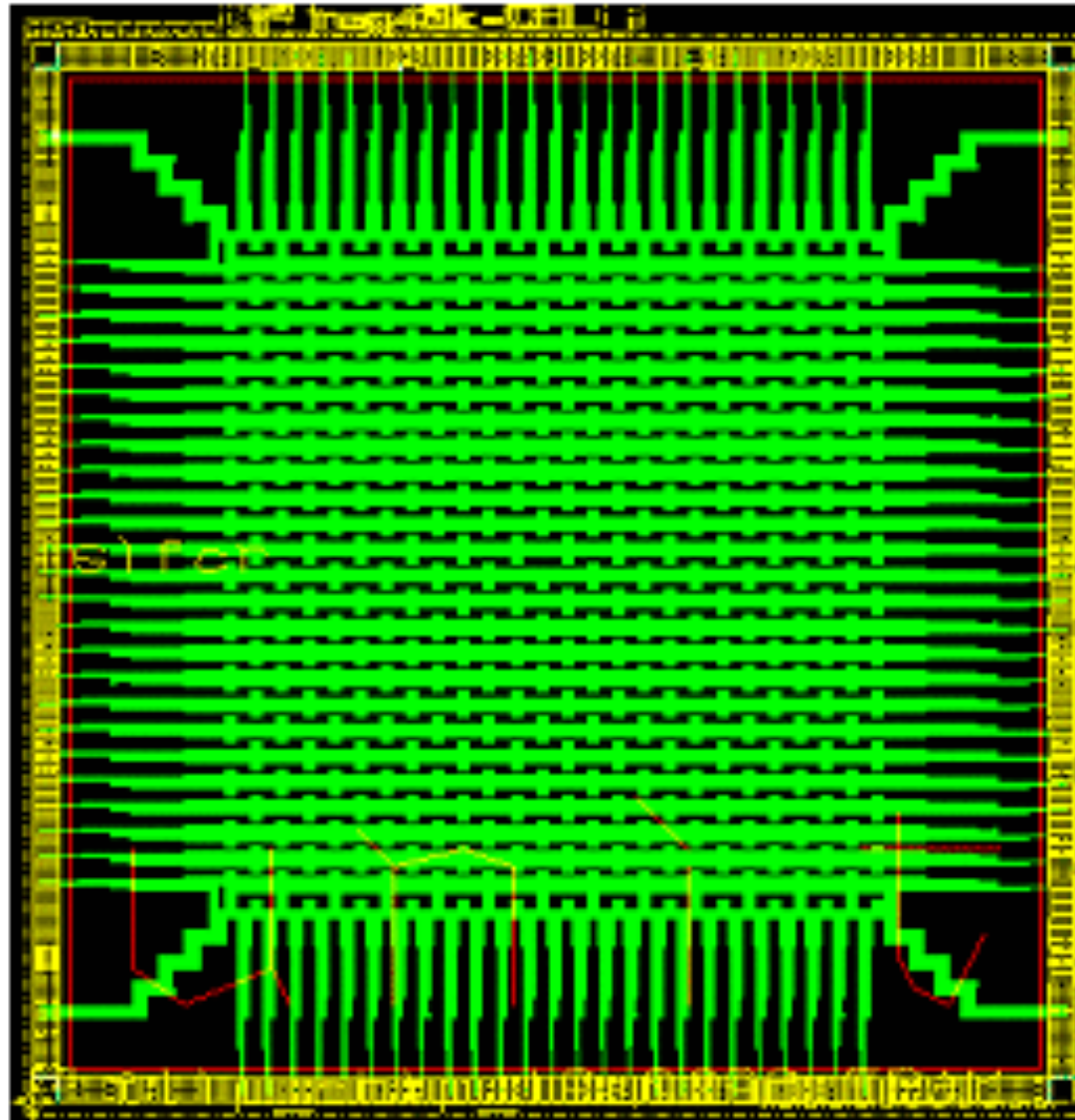


# AMD Jaguar Floorplan

"JAGUAR" CORE FLOOR PLAN

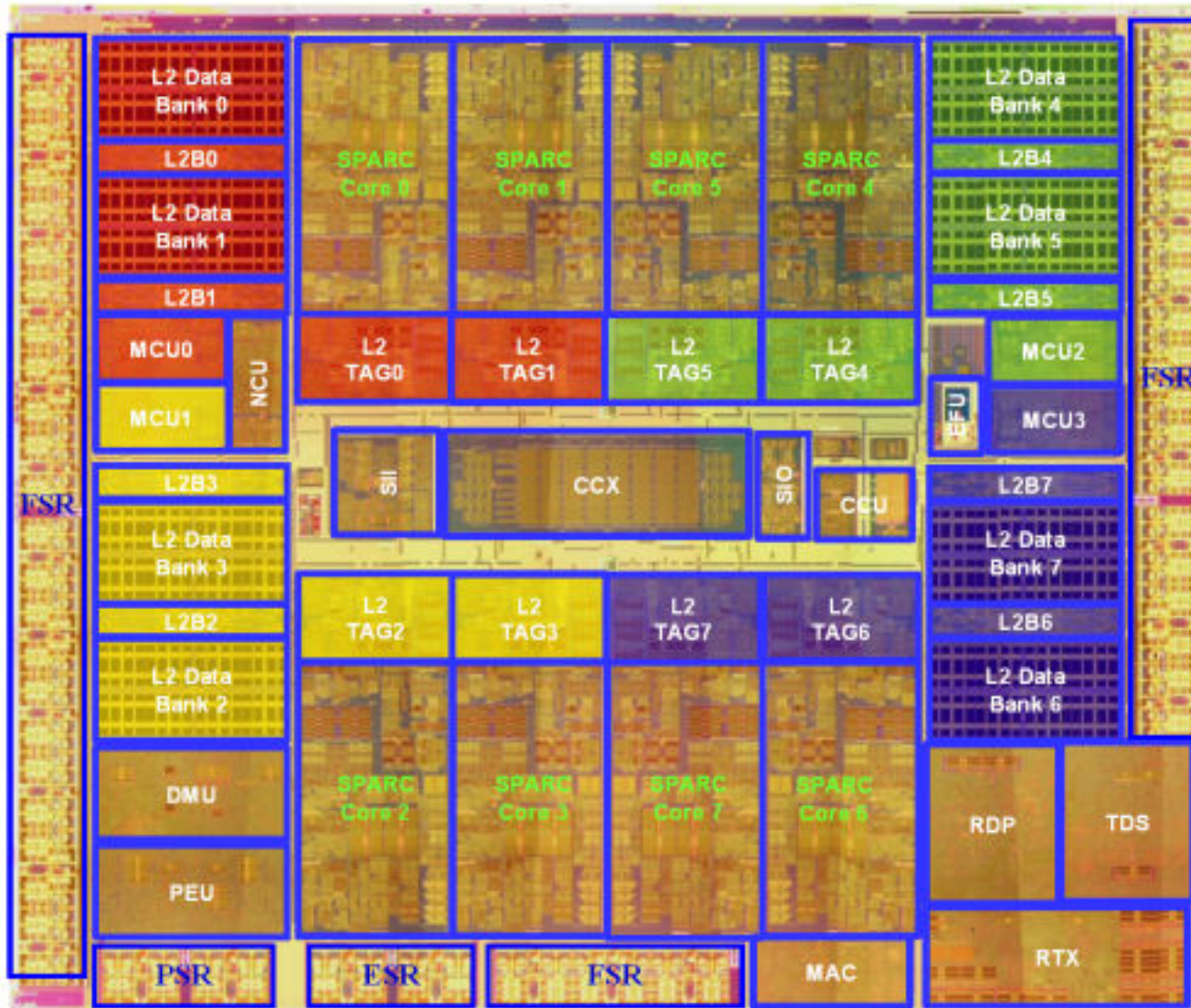


# Flip chip power mesh for AMD Jaguar

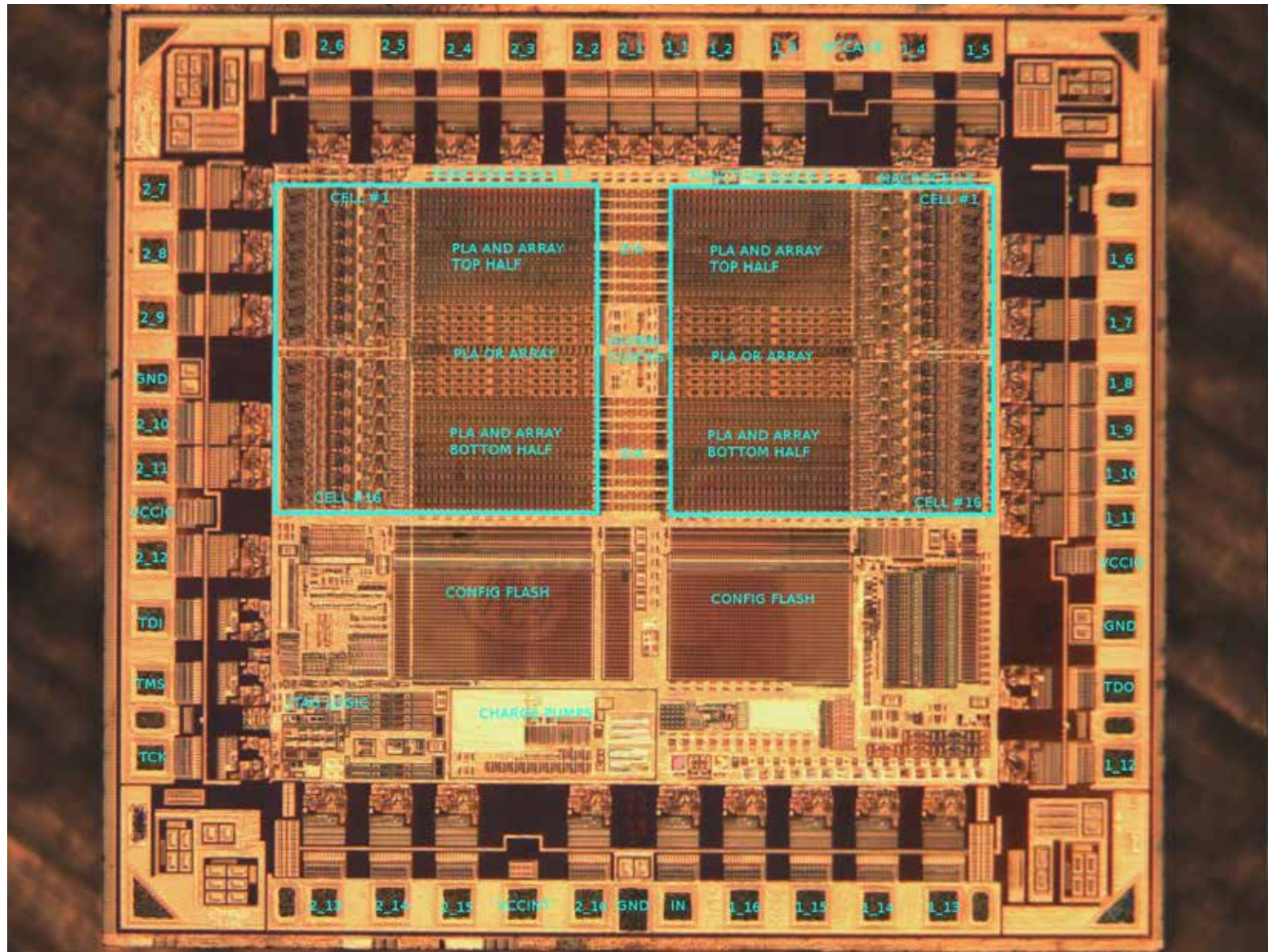


Flip-Chip  
Power Mesh  
(Top Layer)

# SPARC Multicore Processor



# Xilinx XC2C32A CPLD



# Analog Devices LNA

